

Notice of References Cited	Application/Control No. 09/683,546	Applicant(s)/Patent Under Reexamination HAYES, JERRY D.
	Examiner A. M. Thompson	Art Unit 2825

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	A	US-20020183990	12-2002	Wasynczuk et al.	703/2
	B	US-6,028,995	02-2000	Jetton et al.	716/3
	C	US-5,692,160	11-1997	Sarin	703/23
	D	US-6,041,169	03-2000	Brennan	716/6
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	M	US-			

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NON-PATENT DOCUMENTS

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	U	Stievano et al., Parametric Macromodels of Digital I/O Ports, IEEE Transactions on Advanced Packaging, pages 255-264, May 2002.
	V	Stievano et al., Behavioral Modeling of Digital IC Input and Output Ports, Electrical Performance of Electronic Packaging, pages 331-334, October 2001.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.